



Sheet 1 of 1

<b>FORM PTO-1449</b> <b>U.S. DEPARTMENT OF COMMERCE</b> <b>PATENT AND TRADEMARK OFFICE</b>  <b>LIST OF REFERENCES CITED BY APPLICANT</b>  <i>(Use several sheets if necessary)</i>	ATTORNEY DOCKET NO.	APPLICATION NO.
	392.1680	09/546,214
	FIRST NAMED INVENTOR	
	Atsushi WATANABE et al.	
	FILING DATE	GROUP ART UNIT
	April 10, 2000	<del>2721</del> 2621

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
VL	AA	5,845,048	12/01/98	Masumoto			

**FOREIGN PATENT DOCUMENTS**

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES NO	
VL	AB	2 085 629	04/28/82	United Kingdom				

**OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)**

				TRANSLATION YES NO	
VL	AC	Ichiro Masaki, "Industrial Vision Systems Based on Application-Specific IC Chips", IEICE Transactions, Institute of Electronics, Vol. E74 No. 6, June 1, 1991, pages 1728-1734			
VL	AD	Michael Magee et al, "An Industrial Model Based Computer Vision System", Journal of Manufacturing Systems, Society of Manufacturing Engineers, Vol. 14 No. 3, 1995, pages 169-186			
VL	AE	Sarah Wang et al, "Model-Based Vision for Robotic Manipulation of Twisted Tubular Parts: Using Affine Transforms and Heuristic Search", Robotics and Automation, IEEE, May 8, 1994, pages 208-215			
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VL	AG	Toshiyuki Amano et al, "Eignespace Approach for Object Recognition and Its Pose Detection", Systems and Computer in Japan, Vol. 31 No. 11, October 2000, pages 60-69			
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VL	AI	Juan Andrade-Cetto et al., Object Recognition, "Wiley Encyclopedia of Electrical Engineering", April 1, 2000, pages 449-470			

EXAMINER	DATE CONSIDERED
/Vu Le/	04/28/2006
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	